

Direct digitization and ADC parameter trade-off for bunch-by-bunch signal processing

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Outline

- Introduction
 - Direct digitization of bunch signals in beam instrumentation
 - ADC parameter trade-off



Outline



- Introduction
- Analysis of the error in the energy measurement of a direct digitally acquired pulse signal
 - The effect of a limited sampling rate
 - The effect of a limited sampling resolution
 - A combined SNR expression



Outline



- Introduction
- Analysis of the error in the energy measurement of a direct digitally acquired pulse
- Application example
 - A proposed architecture for the LHC BPM read-out electronics
 - Expected position resolution with commercial ADCs







- Introduction
- Analysis of the error in the energy measurement of a direct digitally acquired pulse
- Application example
- Summary









Direct digitization in Beam Instrumentation





Direct digitization in Beam Instrumentation







Direct digitization in Beam Instrumentation

- Less analogue components
 - Less parameter spread
 - Less parameter drifts effects
- Reprogrammable algorithms
- BUT demanding requirements in terms of resolution and sampling rate on the digitization stage



Analog to Digital Converter trade-off





Analysis of the error in the power measurement of a direct digitally acquired pulse signal



Problem Definition



Power measurement of a pulsed signal



Problem Definition



Power measurement of a pulsed signal

$$P_T = \frac{1}{T} \int_0^T |x(t)|^2 dt \qquad \qquad \overline{P_T} = \frac{1}{N} \sum_{n=0}^{N-1} (\hat{x}_{n,\tau} + \nu_n)^2$$

• Is $\overline{P_T}$ a good estimation of P_T ?

- What is the effect of a limited unsynchronised sampling rate?
- What is the effect of the finite resolution of the converter?





Energy and power in time and frequency domain





Energy and power in time and frequency domain







Energy and power in time and frequency domain





Energy and power in time and frequency domain





What happens when we sample the pulse





What happens when we sample the pulse





What happens when we sample the pulse





What happens when we sample the pulse





What happens when we sample the pulse





What happens when we sample the pulse





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What happens when we sample the pulse







And the energy estimation?





And the energy estimation?

• If the Nyquist-Shannon criterion is met ($F_s > R_{Nyq}$)

$$\implies \widehat{P_T} = P_T = \frac{E}{T}$$

• BUT what if $F_s < R_{Nyq}$?





And the energy estimation?





And the energy estimation?





The estimation error

$$\epsilon(X_k, F_s, \tau) \triangleq \widehat{P_T} - P_T$$

 $\epsilon(X_k, F_s, \tau) = A_{X_k, N} \cdot 2\cos(2\pi F_s \tau) + B_{X_k, N} \cdot 2\sin(2\pi F_s \tau)$

$$A_{X_k,N} \triangleq \sum_{\substack{k=0\\N-1}}^{N-1} |X_k| |X_{k-N}| \cdot \cos(\varphi_k - \varphi_{k-N})$$
$$B_{X_k,N} \triangleq \sum_{k=0}^{N-1} |X_k| |X_{k-N}| \cdot \sin(\varphi_k - \varphi_{k-N})$$





The estimation error

$$\epsilon(X_k, F_s, \tau) \triangleq \widehat{P_T} - P_T$$



$$\epsilon(X_k, F_s, \tau) = A_{X_k, N} \cdot 2\cos(2\pi F_s \tau) + \frac{B_{X_k, N}}{2} \cdot 2\sin(2\pi F_s \tau)$$

Hyp:
$$\tau = U\left[0, \frac{1}{F_s}\right]$$

• $\mu_{\epsilon} = 0;$
• $\sigma_{\epsilon}^2 = 2\left(\left(A_{X_k,N}\right)^2 + \left(B_{X_k,N}\right)^2\right)$





The introduction of the converter noise $\boldsymbol{\nu}$

- We now take into account the limited resolution of the ADC
- How does it propagate in the estimator?



• Zero-mean Gaussian variable, with σ_v^2 variance





The introduction of the converter noise $\boldsymbol{\nu}$

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- How does it propagate in the estimator?

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The introduction of the converter noise $\boldsymbol{\nu}$

$$\eta \triangleq \overline{P_T} - \widehat{P_T}$$

$$\mu_{\eta} = \sigma_{\nu}^2 \qquad \qquad \sigma_{\eta}^2 = \frac{\sigma_{\nu}^4}{N} + 4P_T \frac{\sigma_{\nu}^2}{N}$$





Total error

$$\overline{P_T} = \frac{1}{N} \sum_{n=0}^{N-1} (\hat{x}_n + \nu_n)^2 = P_T$$







Total error

$$\overline{P_T} = \frac{1}{N} \sum_{n=0}^{N-1} (\hat{x}_n + \nu_n)^2 = P_T + \epsilon(X_k, F_s, \tau)$$







Total error

$$\overline{P_T} = \frac{1}{N} \sum_{n=0}^{N-1} (\hat{x}_n + \nu_n)^2 = P_T + \epsilon(X_k, F_s, \tau) + \eta(P_T, \sigma_v^2, F_s)$$







Total error

$$\overline{P_T} = \frac{1}{N} \sum_{n=0}^{N-1} (\hat{x}_n + \nu_n)^2 = P_T + \epsilon(X_k, F_s, \tau) + \eta(P_T, \sigma_v^2, F_s)$$

• Mean value:





$$SNR_{dB} = 10 \log_{10} \left(\frac{P_T^2}{2 \left(\left(A_{X_k, N} \right)^2 + \left(B_{X_k, N} \right)^2 \right) + \frac{\sigma_v^4}{N} + 4P_T \frac{\sigma_v^2}{N} \right)$$























Application example

A proposed new bunch-by-bunch read-out system for the LHC BPM





Before the ADC: electrodes combination





Before the ADC: electrodes combination





Before the ADC: electrodes combination





Before the ADC: signal "stretching" with LP filter





Single bunch pulse signal

- LP Filter
 - 200 MHz ۲
 - N=4 ۲
- Antialiasing
 - 600 MHz •
 - N=8 •





Single bunch pulse signal

- LP Filter
 - 200 MHz
 - N=4
- Antialiasing
 - 600 MHz
 - N=8





Power measurement SNR Analysis

$$SNR_{dB} = 10 \log_{10} \left(\frac{P_T^2}{2\left(\left(A_{X_k,N} \right)^2 + \left(B_{X_k,N} \right)^2 \right) + \frac{\sigma_v^4}{N} + 4P_T \frac{\sigma_v^2}{N} \right)} \right)$$



Power measurement SNR Analysis



$$SNR_{dB} = 10 \log_{10} \left(\frac{P_T^2}{2 \left((A_{X_k,N})^2 + (B_{X_k,N})^2 \right) + \frac{\sigma_V^4}{N} + 4P_T \frac{\sigma_V^2}{N} \right)} - \frac{\sigma_V^4}{N} + 4P_T \frac{\sigma_V^2}{N} + 4P_T \frac{\sigma_V^2}{N} - \frac{\sigma_V^4}{N} - \frac{\sigma_V^$$



Power measurement SNR Analysis





Position Resolution Analysis





With transmission bandwidth limit





Summary



Summary



- **Direct digitization** based systems are of growing interest for Beam Instrumentation applications.
- ADC state-of-the-art imposes a **trade-off** between sampling rate and resolution.
- It is possible to estimate the error introduced in the energy estimation of a digitized pulse as a function of the sampling rate and resolution.
- This analytic tool can facilitate the analysis of the performance of a system, but also assist in the design of a new system, especially in the selection of the ADC.